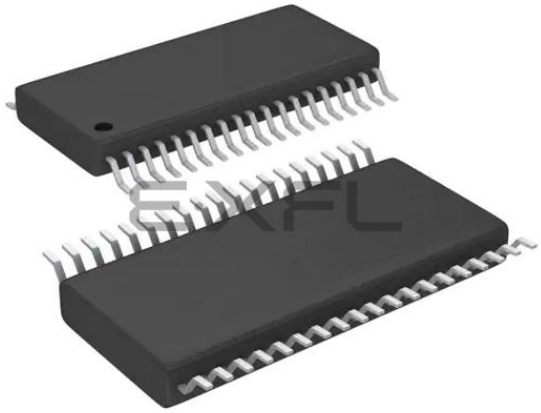
Infineon Technologies - XMC1201T028F0016ABXUMA1 Datasheet



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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	20
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 14x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	38-TFSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-38-9
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1201t028f0016abxuma1

XMC1200

Microcontroller Series
for Industrial Applications

XMC1000 Family

ARM® Cortex™-M0
32-bit processor core

Data Sheet

V1.4 2014-05

Microcontrollers

- Push/pull or open drain output mode
- Configurable pad hysteresis

On-Chip Debug Support

- Support for debug features: 4 breakpoints, 2 watchpoints
- Various interfaces: ARM serial wire debug (SWD), single pin debug (SPD)

1.1 Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. The code “XMC1<DDD>-<Z><PPP><T><FFFF>” identifies:

- <DDD> the derivatives function set
- <Z> the package variant
  - T: TSSOP
  - Q: VQFN
- <PPP> package pin count
- <T> the temperature range:
  - F: -40°C to 85°C
  - X: -40°C to 105°C
- <FFFF> the Flash memory size.

For ordering codes for the XMC1200 please contact your sales representative or local distributor.

This document describes several derivatives of the XMC1200 series, some descriptions may not apply to a specific product. Please see **Table 1**.

For simplicity the term **XMC1200** is used for all derivatives throughout this document.

1.2 Device Types

These device types are available and can be ordered through Infineon’s direct and/or distribution channels.

Table 1 Synopsis of XMC1200 **Device Types**

Derivative	Package	Flash Kbytes	SRAM Kbytes
XMC1201-T038F0016	PG-TSSOP-38-9	16	16
XMC1201-T038F0032	PG-TSSOP-38-9	32	16
XMC1201-T038F0064	PG-TSSOP-38-9	64	16
XMC1201-T038F0128	PG-TSSOP-38-9	128	16
XMC1201-T038F0200	PG-TSSOP-38-9	200	16

Table 4 XMC1200 Chip Identification Number (cont'd)

Derivative	Value	Marking
XMC1202-T016X0016	00012033 01CF00FF 00001FF7 00008000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1202-T016X0032	00012033 01CF00FF 00001FF7 00008000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1202-Q024X0016	00012063 01CF00FF 00001FF7 00008000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1202-Q024X0032	00012063 01CF00FF 00001FF7 00008000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1201-Q040F0016	00012042 01CF00FF 00001FF7 00006000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1201-Q040F0032	00012042 01CF00FF 00001FF7 00006000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1201-Q040F0064	00012042 01CF00FF 00001FF7 00006000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1201-Q040F0128	00012042 01CF00FF 00001FF7 00006000 00000B00 00001000 00021000 $101ED083_H$	AA
XMC1201-Q040F0200	00012042 01CF00FF 00001FF7 00006000 00000B00 00001000 00033000 $101ED083_H$	AA
XMC1202-Q040X0016	00012043 01CF00FF 00001FF7 00008000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1202-Q040X0032	00012043 01CF00FF 00001FF7 00008000 00000B00 00001000 00009000 $101ED083_H$	AA

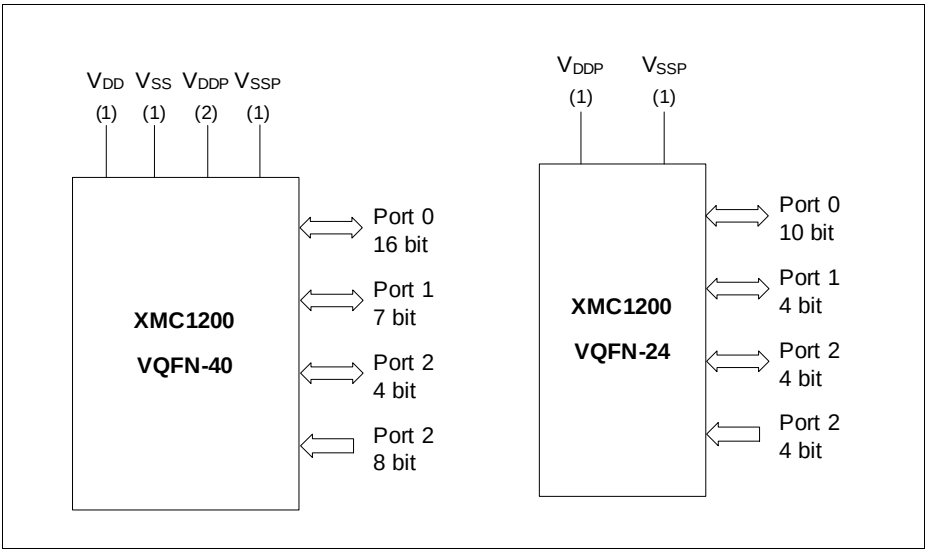

Figure 3 XMC1200 Logic Symbol for VQFN-24 and VQFN-40

2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the different packages.

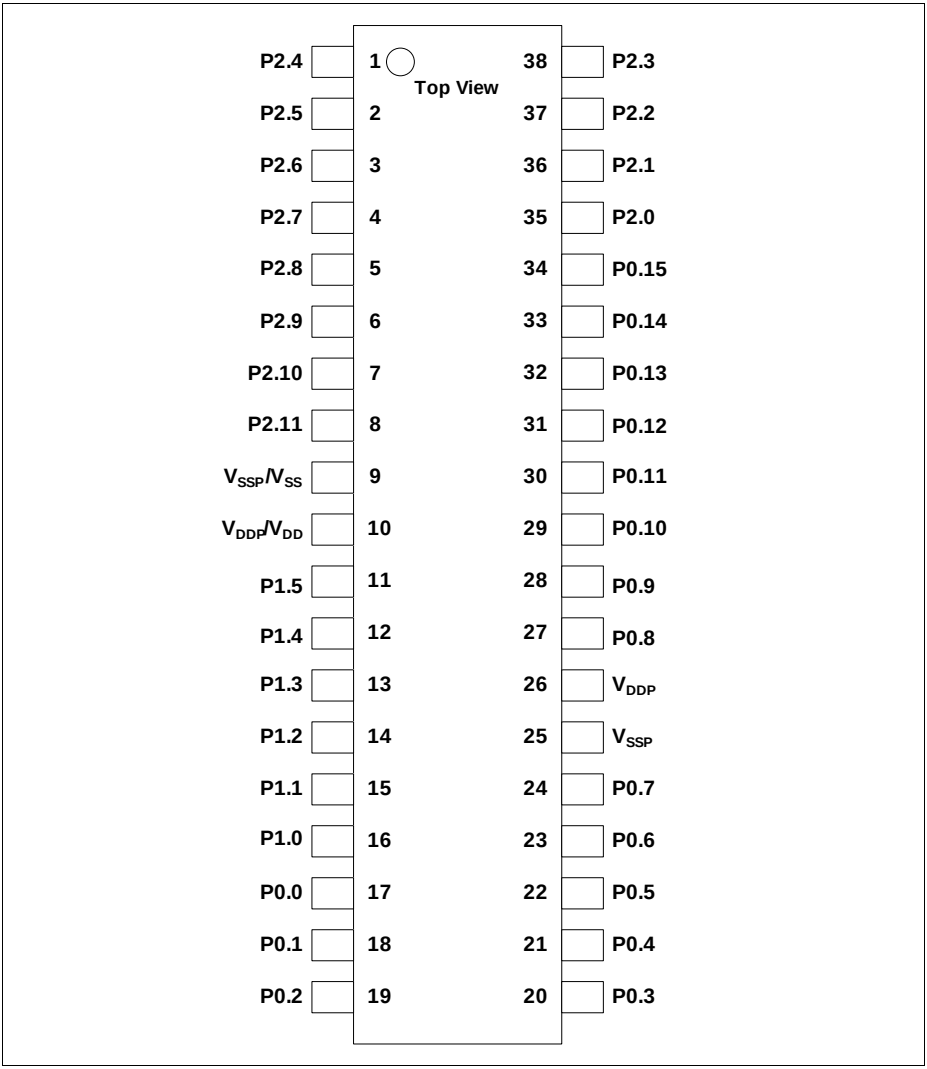

Figure 4 XMC1200 PG-TSSOP-38 Pin Configuration (top view)

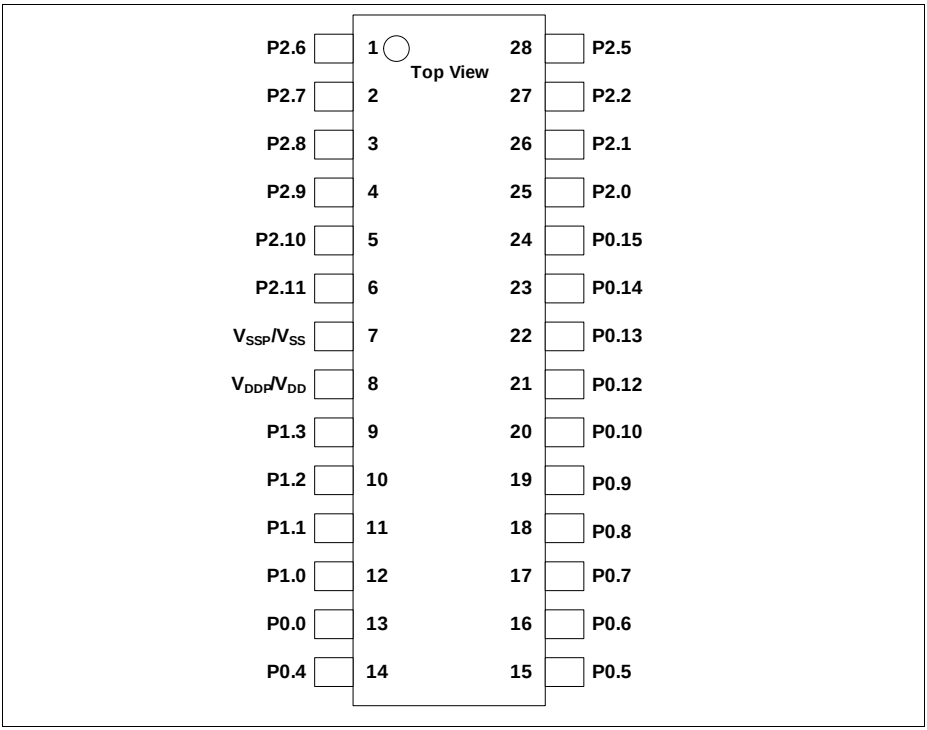

Figure 5 XMC1200 PG-TSSOP-28 Pin Configuration (top view)

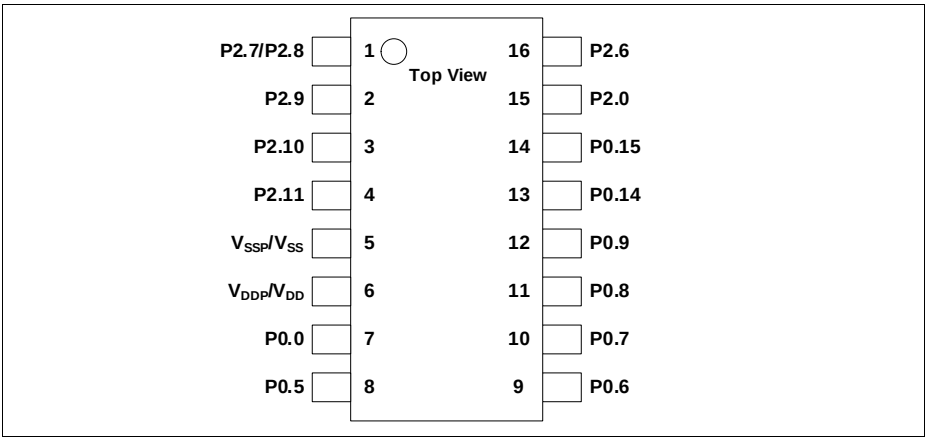

Figure 6 XMC1200 PG-TSSOP-16 Pin Configuration (top view)

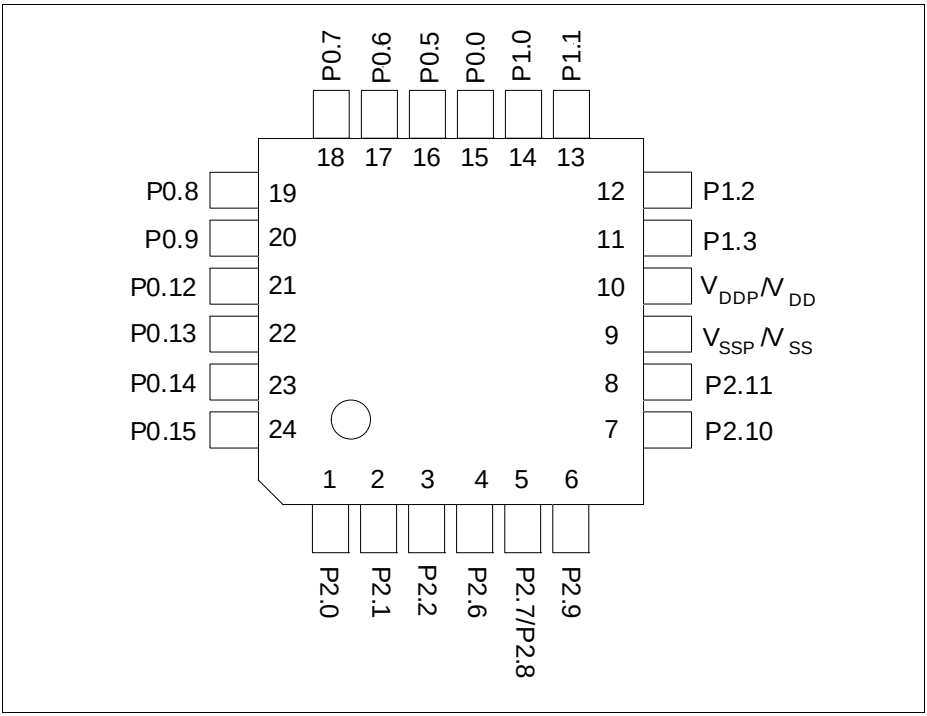

Figure 7 XMC1200 PG-VQFN-24 Pin Configuration (top view)

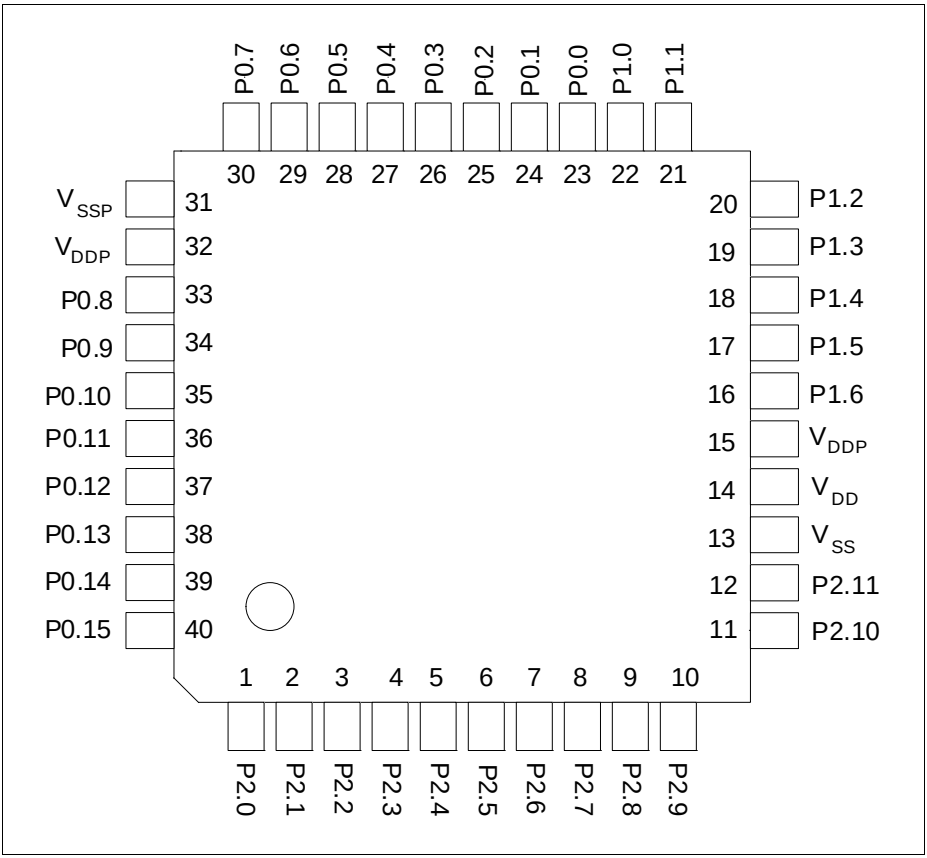

Figure 8 XMC1200 PG-VQFN-40 Pin Configuration (top view)

3 Electrical Parameter

This section provides the electrical parameter which are implementation-specific for the XMC1200.

3.1 General Parameters

3.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XMC1200 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the “Symbol” column:

- **CC**
  Such parameters indicate **C**ontroller **C**haracteristics, which are distinctive feature of the XMC1200 and must be regarded for a system design.
- **SR**
  Such parameters indicate **S**ystem **R**equirements, which must be provided by the application system in which the XMC1200 is designed in.

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 9 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_S	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on any pin with respect to V_{SSP}	V_{IN}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	whichever is lower
Voltage on any analog input pin with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	–
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute sum of all input currents during overload condition	$\Sigma\|I_{IN}\|$	SR	–	–	50	mA	–
Analog comparator input voltage	V_{CM}	SR	-0.3	–	V_{DDP} + 0.3	V	

Table 11 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Maximum current into V_{DDP} (TSSOP28/16, VQFN24)	I_{MVDD1}	SR	–	130	mA	3)
Maximum current into V_{DDP} (TSSOP38, VQFN40)	I_{MVDD2}	SR	–	260	mA	3)
Maximum current out of V_{SS} (TSSOP28/16, VQFN24)	I_{MVSS1}	SR	–	130	mA	3)
Maximum current out of V_{SS} (TSSOP38, VQFN40)	I_{MVSS2}	SR	–	260	mA	3)

1) Not subject to production test, verified by design/characterization. Hysteresis is implemented to avoid meta stable states and switching due to internal ground bounce. It cannot be guaranteed that it suppresses switching due to external system noise.

2) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin.

3) Not subject to production test, verified by design/characterization.

4) Not subject to production test, verified by design/characterization. However, for applications with strict low power-down current requirements, it is mandatory that no active voltage source is supplied at any GPIO pin when V_{DDP} is powered off.

3.2.3 Out of Range Comparator (ORC) Characteristics

The Out-of-Range Comparator (ORC) triggers on analog input voltages (V_{AIN}) above the V_{DDP} on selected input pins (ORCx.AIN) and generates a service request trigger (ORCx.OUT).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 13 Out of Range Comparator (ORC) Characteristics (Operating Conditions apply; V_{DDP} = 3.0 V - 5.5 V)

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
DC Switching Level	V_{ODC}	CC	60	–	120	mV	$V_{AIN} \geq V_{DDP} + V_{ODC}$
Hysteresis	V_{OHYS}	CC	25	–	V_{ODC}	mV	
Always detected Overvoltage Pulse	t_{OPDD}	CC	103	–	–	ns	$V_{AIN} \geq V_{DDP}$ + 150 mV
			88	–	–	ns	$V_{AIN} \geq V_{DDP}$ + 350 mV
Never detected Overvoltage Pulse	t_{OPDN}	CC	–	–	21	ns	$V_{AIN} \geq V_{DDP}$ + 150 mV
			–	–	11	ns	$V_{AIN} \geq V_{DDP}$ + 350 mV
Detection Delay	t_{ODD}	CC	39	–	132	ns	$V_{AIN} \geq V_{DDP}$ + 150 mV
			31	–	121	ns	$V_{AIN} \geq V_{DDP}$ + 350 mV
Release Delay	t_{ORD}	CC	44	–	240	ns	$V_{AIN} \leq V_{DDP}$; V_{DDP} = 5 V
			57	–	340	ns	$V_{AIN} \leq V_{DDP}$; V_{DDP} = 3.3 V
Enable Delay	t_{OED}	CC	–	–	300	ns	ORCCTRL.ENORCx = 1

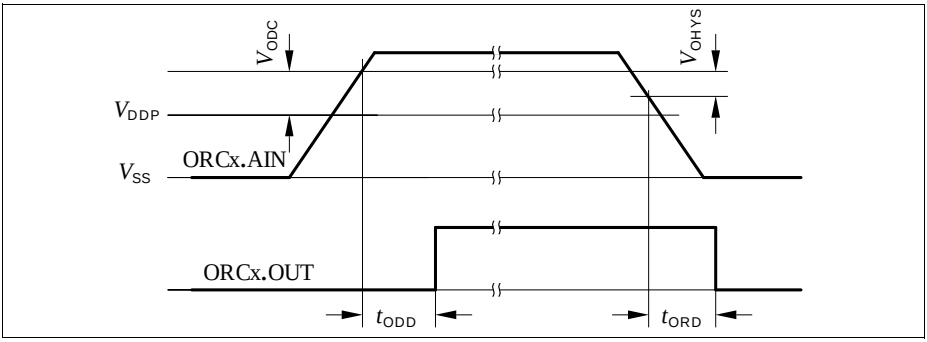

Figure 10 ORCx.OUT Trigger Generation

Table 17 provides the active current consumption of some modules operating at 5 V power supply at 25 °C. The typical values shown are used as a reference guide on the current consumption when these modules are enabled.

Table 17 Typical Active Current Consumption[1)]

Active Current Consumption	Symbol	Limit Values	Unit	Test Condition
		Typ.		
Baseload current	I_{CPUDDC}	5.04	mA	Modules including Core, SCU, PORT, memories, ANATOP[2)]
VADC and SHS	I_{ADCDDC}	3.4	mA	Set CGATCLR0.VADC to 1[3)]
USIC0	$I_{USIC0DDC}$	0.87	mA	Set CGATCLR0.USIC0 to 1[4)]
CCU40	$I_{CCU40DDC}$	0.94	mA	Set CGATCLR0.CCU40 to 1[5)]
LEDTSx	$I_{LTSxDDC}$	0.76	mA	Set CGATCLR0.LEDTSx to 1[6)]
BCCU0	$I_{BCCU0DDC}$	0.24	mA	Set CGATCLR0.BCCU0 to 1[7)]
WDT	I_{WDTDDC}	0.03	mA	Set CGATCLR0.WDT to 1[8)]
RTC	I_{RTCDDC}	0.01	mA	Set CGATCLR0.RTC to 1[9)]

1) Not subject to production test, verified by design/characterisation.

2) Baseload current is measured with device running in user mode, MCLK=PCLK=32 MHz, with an endless loop in the flash memory. The clock to the modules stated in CGATSTAT0 are gated.

3) Active current is measured with: module enabled, MCLK=32 MHz, running in auto-scan conversion mode

4) Active current is measured with: module enabled, alternating messages sent to PC at 57.6kbaud every 200ms

5) Active current is measured with: module enabled, MCLK=PCLK=32 MHz, 1 CCU4 slice for PWM switching from 1500Hz and 1000Hz at regular intervals, 1 CCU4 slice in capture mode for reading period and duty cycle

6) Active current is measured with: module enabled, MCLK=32 MHz, 1 LED column, 6 LED/TS lines, Pad Scheme A with large pad hysteresis config, time slice duration = 1.048 ms

7) Active current is measured with: module enabled, MCLK=32 MHz, PCLK=64MHz, FCLK=0.8MHz, Normal mode (BCCU Clk = FCLK/4), 3 BCCU Channels and 1 Dimming Engine, change color or dim every 1s

8) Active current is measured with: module enabled, MCLK=32 MHz, time-out mode; WLB = 0, WUB = 0x00008000; WDT serviced every 1s

9) Active current is measured with: module enabled, MCLK=32 MHz, Periodic interrupt enabled

3) Valid for a 100 nF buffer capacitor connected to supply pin where current from capacitor is forwarded only to the chip. A larger capacitor value has to be chosen if the power source sink a current.

4) This values does not include the ramp-up time. During startup firmware execution, MCLK is running at 32 MHz and the clocks to peripheral as specified in register CGATSTAT0 are gated.

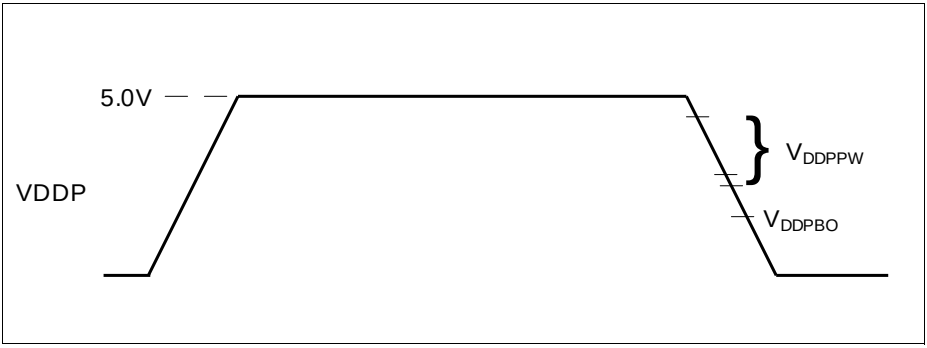

Figure 14 Supply Threshold Parameters

3.3.5 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 23 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	–	500000	ns	–
SWDCLK low time	t_2 SR	50	–	500000	ns	–
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	–	–	ns	–
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	–	–	ns	–
SWDIO output valid time after SWDCLK rising edge	t_5 CC	–	–	68	ns	C_L = 50 pF
		–	–	62	ns	C_L = 30 pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	–	–	ns	

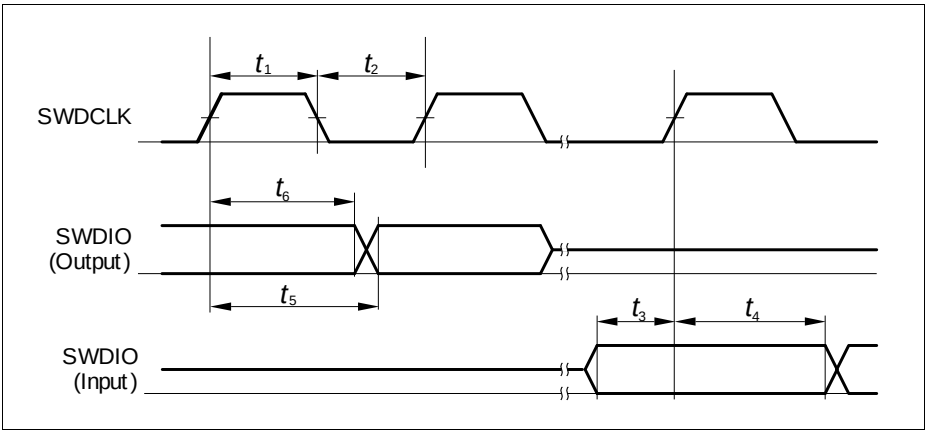

Figure 16 SWD Timing

Table 28 USIC IIC Fast Mode Timing [1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	20 + 0.1*C_b [2)]	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	20 + 0.1*C_b	-	300	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	100	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	1.3	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	0.6	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	0.6	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	0.6	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	0.6	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	1.3	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximalely 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2) C_b refers to the total capacitance of one bus line in pF.

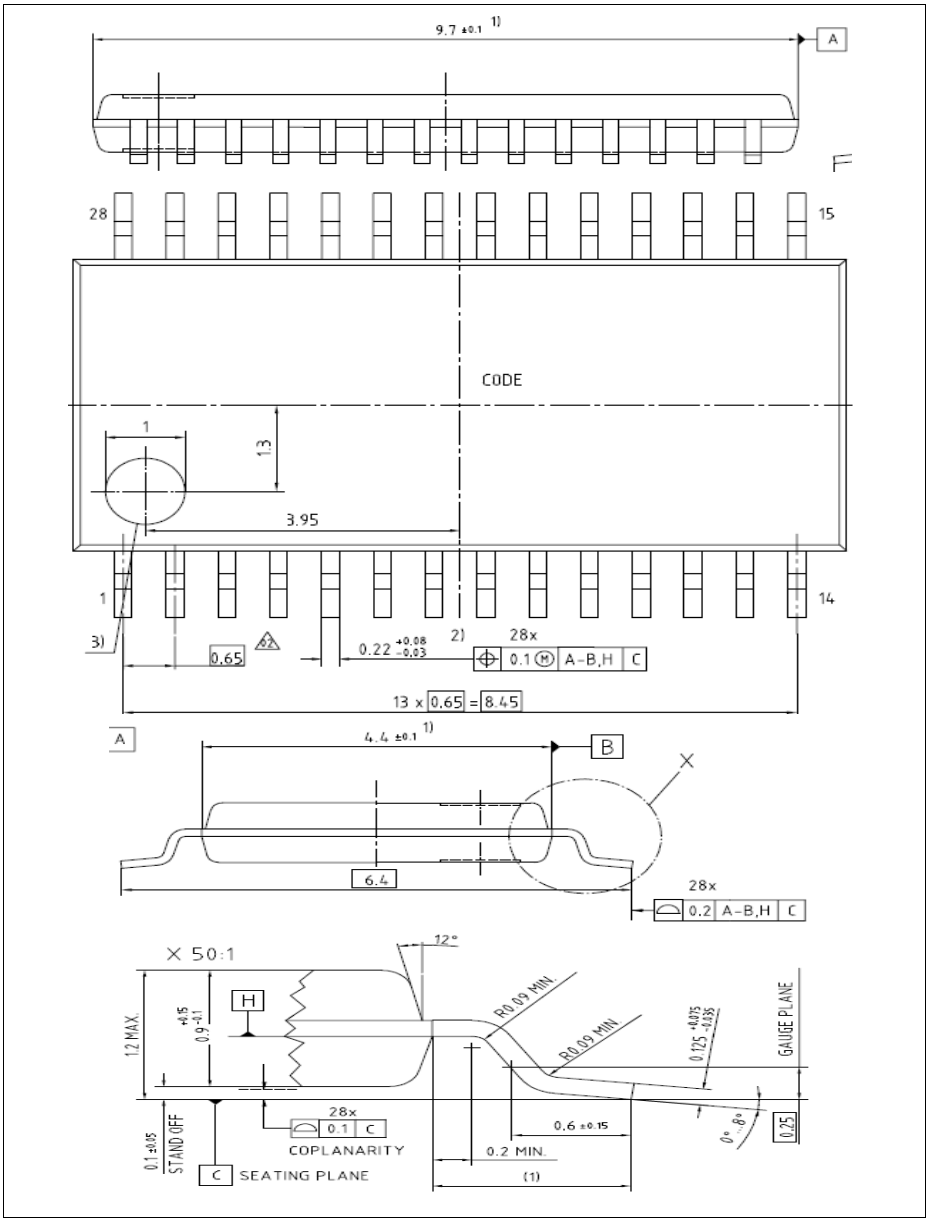

Figure 22 PG-TSSOP-28-16

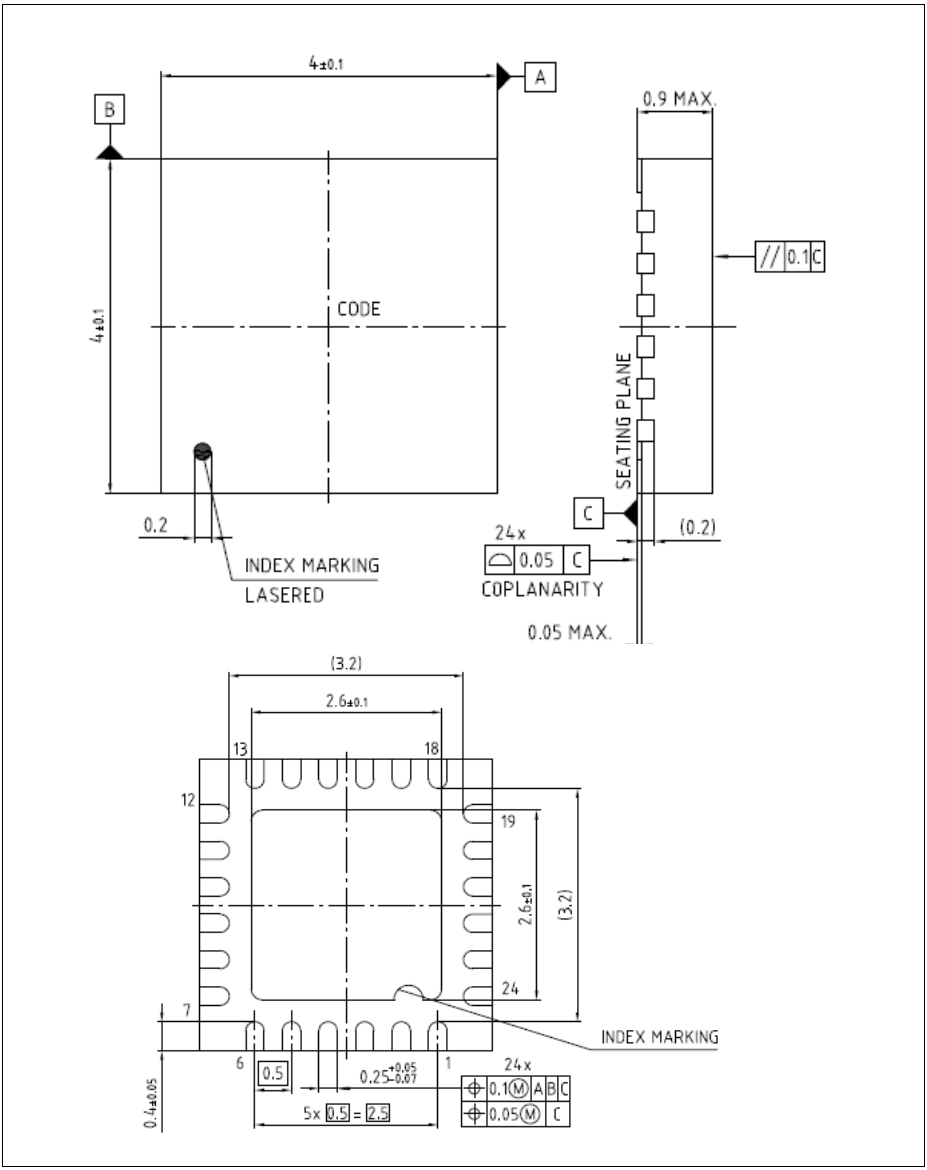

Figure 24 PG-VQFN-24-19

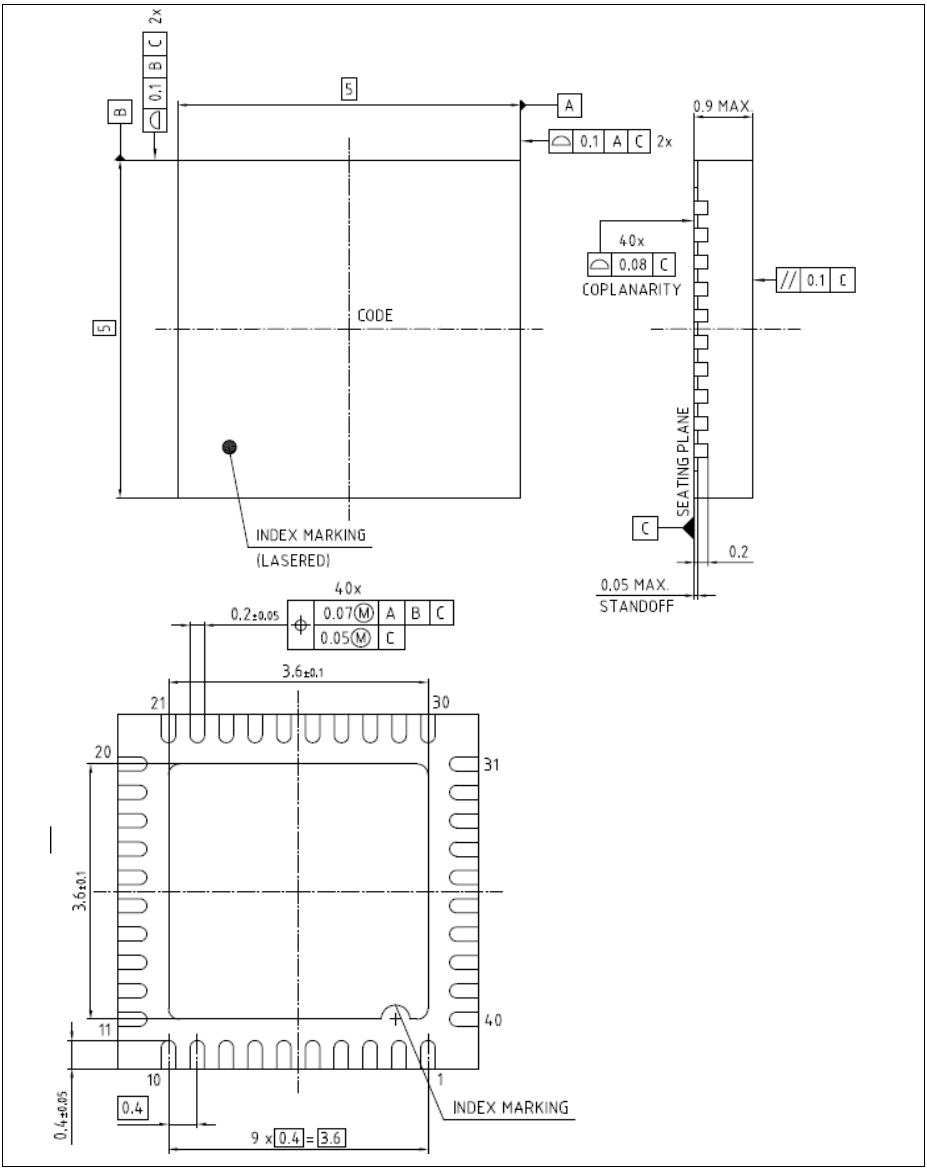

Figure 25 PG-VQFN-40-13

All dimensions in mm.

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